# Development and characterization of novel electronics for the search of dark matter for DAMIC-M

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#### Giorgos PAPADOPOULOS



#### DAMIC : DArk Matter In CCDs



# **Dark Matter (DM) motivation**

**Evidence**:

- Galaxy rotation curve [1]
- CMB power spectrum [2]
- Weak field lensing of colliding ۶ galaxy clusters [3]
- Mass to luminosity ratio[4] ۶

Up to date status:



90

6<sup>h</sup>58<sup>m</sup>42<sup>s</sup>





#### DM current status

DAMIC : DArk Matter In CCDs



DAMIC-M: search for light WIMPs and hidden sector DM with mass <10GeV.



WIMP-nucleon cross sections for Spin-Independent coupling versus mass [5,6]

# Charge Coupled Device (CCD)

#### DAMIC : DArk Matter In CCDs





- Direct detection:  $\chi$  + SM  $\rightarrow \chi$  + SM
- CCD is made of silicon, separated in pixels
- Incident particles deposit energy in the bulk



Real CCD image on surface level

### **CCD** Operation



# Readout

charge transfer and recording

# **CCD** Operation

#### 1. Charge generation - Exposure



#### 2. Charge collection - Exposure



CCD single pixel.

- 3 electrodes: 1 "active"
- Charge collection under the active electrode
- Size: 15 µm x 15 µm

#### 3. Charge transfer - Readout



• Move the charge by alternating the voltage of the electrodes (vertical and horizontal clocks) to the Readout circuit

### CCD readout circuit





Reaching the end of the CCD, there is a circuit to convert the pixel charge into voltage.

- The Reset Gate sets the Sense Node at a voltage reference value. This will cause a bump in the output signal which will decay quickly, resulting in an outcome reference level *around* Vref.
- The charge *Q* is injected to the SN changing the voltage by  $V_q = Q / C_s$ , where  $C_s$  is the capacity of the sense node which is known.
- Measure and subtract the reference and signal levels to find the  $V_o$ .

### CCD noise sources

#### Dark current

- Thermally generated electrons in the bulk of the CCD
- Linear dependence on time → limits the exposure duration. The longer the exposure, the worse the Signal to Noise Ratio.
- Lower the temperature (~100-140K) to decrease the dark current

#### Reset or kTC noise

- After reset pulse thermal noise is generated by the resistance of the reset FET. The small capacitance of the Sense Node ~fF leads to a significant uncertainty of the reference level.
- Correlated Double Sampling (CDS): measure both the reference and signal levels and subtract them to eliminate the reset noise.



#### <u>White noise</u>

Thermal noise generated by the output amplifier MOSFET.

#### Flicker or 1/f noise

- The *flicker* noise depends approximately on the inverse of the sampling frequency.
- Dominant up to ~0.1MHz readout speed



### Skipper CCD – sub- $e^-$ resolution

Single e resolution spectrum



Count [/0.2 ADU] DAMIC-M, LPNHE 1k x 6k Skipper CCD NDCM = 1000Integration time =  $10\mu s$ 150 100 sigma =  $0.18 e^{-1}$ 50 -20 20 60 80 0 40 100 -40Zeroed Pixel Value [ADU]

The Skipper technique allows for a Non-Destructive Multiple pixel Charge Measurement (NDCM) which reduce the electronic noise which decreases as 1/√NDCM.

### **DAMIC-M** Overview



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DArk Matter In CCDs at Modane (DAMIC-M):

- 50 scientific grade Charge Coupled Devices (CCDs) made of Si with Skipper readout
- 36Mpix large and ~20g each, a total kg-size target mass
- Sub-electron resolution
- 0.1 event/(keV·kg·day) background
- > R&D of the electronics to control the CCD
- > Simulations of the detector design and shielding
- Underground Laboratory in Modane (LSM). ~2km of rock to stop cosmic background.
- Low Background Chamber (2020) test detector to evaluate new CCDs, test electronics and measure background
- > Final experiment data taking will start in 2022.
- DAMIC-M will pioneer in the low mass WIMPs and hidden-sector DM research.
- > ERC grant 2017

## Full Setup & New Electronics

The CCD is placed in a cryostat and is controlled and readout by external electronics.

- All voltages and clocks during the expose and readout phases will be provided by the Clocks And Biases ASIC for CCD (CABAC) board.
- The **CCD ReadOut Chip** (**CROC**) will preprocess and amplify the signal to improve the Signal-to-Noise Ratio.
- An **Analog to Digital Converter (ADC)** will perform the transition from the analog domain to the digital one. The ADC can only apply the conversion in certain specified moments.
- Everything is going to be controlled by the FPGA, the brain of the, so called, ODILE Online Digital Interface for Low-noise Electronics motherboard



Setup of a single DAMIC-M CCD

### **New Electronics**





LTC2387-18 18-bit 15 MHz ADC candidate prototype board

CROC evaluation

ODILE board with MAX11905 20-bit 1.6 MHz ADC candidate



## Near Future

- The CROC chip is operational with low input noise at room temperature
- Test in low temperature  $\rightarrow$  to be done
- Integrate in a setup for real CCD input signals  $\rightarrow$  to be done
- A first version of the fast ADC was evaluated verifying the expected behaviour
- New design compatible with ODILE  $\rightarrow$  in process
- 4CABAC board will be evaluated soon
- An ODILE board with a 20-bit ADC is functional and soon will be tested with a CCD.





65

80 85



#### References :

[1] arXiv:astro-ph/9909252

- [2] arXiv:1507.02704
- [3] arXiv:astro-ph/0608407
- [4] On the masses of nebulae and of clusters of nebulae, F. Zwicky, 1937
- [5] The Review of Particle Physics, M. Tanabashi et al. (Particle Data Group), Phys. Rev. D 98, 030001 (2018)
- [6] DAMIC-M Experiment: Thick, Silicon CCDs to search for Light Dark Matter, N. Castello-Mor for the DAMIC-M Collaboration, 2020